

Abstract Submitted  
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**Noise characterization of an injection-locked ti:sapphire laser**  
DANIEL THRASHER, SCOTT BERGESON — We use a microwave interferometer and an offset frequency lock to characterize the noise properties of an injection-locked ti:sapphire laser. We find a laser linewidth of 2 MHz and an rms amplitude noise of a few percent. In this presentation I will describe the laser, the interferometer, the offset lock, and the measurement results. Our results will be compared with a recently published model.

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